

#13105  
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Finarov, Moshe

Assignee: Nova Measuring Instruments

Title: APPARATUS FOR OPTICAL INSPECTION OF WAFERS DURING  
POLISHING

Serial: 09/047,944

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Examiner: E. Morgan

Group Art Unit: 3723

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San Jose, California  
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ASSISTANT COMMISSIONER FOR PATENTS  
BOX CPA  
Washington, D. C. 20231

**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, § 1.97 and § 1.98, Applicant brings the following documents (copies enclosed) to the Examiner's attention in the above-captioned application.

1. USP 5,658,183 issued 08/19/97 to Sandhu et al.
2. USP 5,486,129 issued 01/23/96 to Sandhu et al.
3. USP 5,643,060 issued 07/01/97 to Sandhu et al.
4. USP 5,730,642 issued 03/24/98 to Sandhu et al.
5. USP 5,762,537 issued 06/09/98 to Sandhu et al.
6. USP 5,700,180 issued 12/23/97 to Sandhu et al.

A PTO form 1449 listing these documents is enclosed.

Citation of the above documents shall not be construed as:

1. an admission that the documents are necessarily prior art with respect to the instant invention;
2. a representation that a search has been made, other than as described above; or

3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

EXPRESS MAIL LABEL NO:

EL 252 576 876 US

Respectfully submitted,



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